



Project Number: Design Qualification Test Report		Tracking Code: 187553_Report_Rev_1	
Requested by: Mark Shireman		Date: 4/20/2012	Product Rev: N/A
Part #: HLE-125-02-L-DV-A\TSM-125-01-L-DV-A HLE-125-02-S-DV-A\TSM-125-01-S-DV-A		Lot #: N/A	Eng: Eric Mings
Part description: HLE/TSM			Qty to test: 16
Test Start: 03/12/2012	Test Completed: 04/06/2012		

DESIGN QUALIFICATION TEST REPORT

HLE\TSM

HLE-125-02-L-DV-A\TSM-125-01-L-DV-A (10u" Gold)

HLE-125-02-S-DV-A\TSM-125-01-S-DV-A (30u" Gold)

Tracking Code: 187553_Report_Rev_1	Part #: HLE-125-02-L-DV-A\TSM-125-01-L-DV-A HLE-125-02-S-DV-A\TSM-125-01-S-DV-A
Part description: HLE/TSM	

CERTIFICATION

All instruments and measuring equipment were calibrated to National Institute for Standards and Technology (NIST) traceable standards according to ISO 10012-1 and ANSI/NCSL 2540-1, as applicable.

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SCOPE

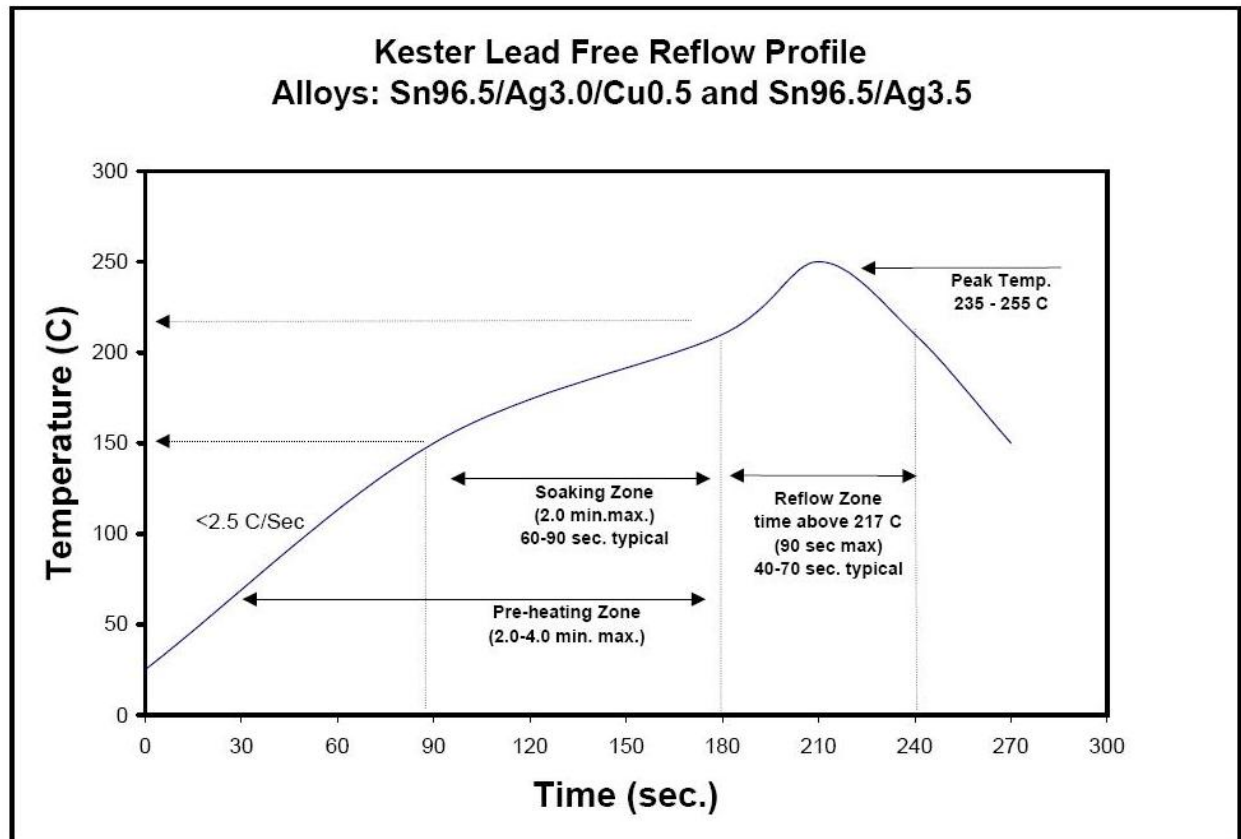
To perform the following tests: Design Qualification test. Please see test plan.

APPLICABLE DOCUMENTS

Standards: EIA Publication 364

TEST SAMPLES AND PREPARATION

- 1) All materials were manufactured in accordance with the applicable product specification.
- 2) All test samples were identified and encoded to maintain traceability throughout the test sequences.
- 3) After soldering, the parts to be used for LLCr testing were cleaned according to TLWI-0001.
- 4) Either an automated cleaning procedure or an ultrasonic cleaning procedure may be used.
- 5) The automated procedure is used with aqueous compatible soldering materials.
- 6) Parts not intended for testing LLCr are visually inspected and cleaned if necessary.
- 7) Any additional preparation will be noted in the individual test sequences.
- 8) Solder Information: Lead Free
- 9) Re-Flow Time/Temp: See accompanying profile.

TYPICAL OVEN PROFILE (Soldering Parts to Test Boards)

FLOWCHARTS**LLCR/Durability**

TEST STEP	GROUP A1 10u" Gold (-L) 8 Mated Sets	GROUP B1 30u" Gold (-S) 8 Mated Sets
01	LLCR-1	LLCR-1
02	100 Cycles	100 Cycles
03	LLCR-2	LLCR-2
04	Thermal Shock (Mated and Undisturbed)	Thermal Shock (Mated and Undisturbed)
05	LLCR-3	LLCR-3
06	Cyclic Humidity (Mated and Undisturbed)	Cyclic Humidity (Mated and Undisturbed)
07	LLCR-4	LLCR-4

Thermal Shock = EIA-364-32, Table II, Test Condition I:

-55°C to +85°C 1/2 hour dwell, 100 cycles

Humidity = EIA-364-31, Test Condition B (240 Hours)

and Method III (+25°C to +65°C @ 90% RH to 98% RH)

ambient pre-condition and delete steps 7a and 7b

LLCR = EIA-364-23, LLCR

20 mV Max, 100 mA Max

Use Keithley 580 or 3706 in 4 wire dry circuit mode

ATTRIBUTE DEFINITIONS

The following is a brief, simplified description of attributes.

THERMAL SHOCK:

- 1) EIA-364-32, *Thermal Shock (Temperature Cycling) Test Procedure for Electrical Connectors*.
- 2) Test Condition 1: -55°C to +85°C
- 3) Test Time: ½ hour dwell at each temperature extreme
- 4) Number of Cycles: 100
- 5) All test samples are pre-conditioned at ambient.
- 6) All test samples are exposed to environmental stressing in the mated condition.

HUMIDITY:

- 1) Reference document: EIA-364-31, *Humidity Test Procedure for Electrical Connectors*.
- 2) Test Condition B, 240 Hours.
- 3) Method III, +25° C to + 65° C, 90% to 98% Relative Humidity excluding sub-cycles 7a and 7b.
- 4) All samples are pre-conditioned at ambient.
- 5) All test samples are exposed to environmental stressing in the mated condition.

LLCR:

- 1) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 2) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 3) The following guidelines are used to categorize the changes in LLCR as a result from stressing
 - a. <= +5.0 mOhms: ----- Stable
 - b. +5.1 to +10.0 mOhms: ----- Minor
 - c. +10.1 to +15.0 mOhms: ----- Acceptable
 - d. +15.1 to +50.0 mOhms: ----- Marginal
 - e. +50.1 to +2000 mOhms: ----- Unstable
 - f. >+2000 mOhms: ----- Open Failure

RESULTS**LLCR Durability****HLE-125-02-L-DV-A\TSM-125-01-L-DV-A (10u" Gold)****192 LLCR test points**

- **Initial** -----9.00mOhms Max
- **Durability 100 cycles**
 - o <= +5.0 mOhms ----- 192 Points ----- Stable
 - o +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - o +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - o +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - o +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - o >+2000 mOhms ----- 0 Points ----- Open Failure
- **Thermal**
 - o <= +5.0 mOhms ----- 192 Points ----- Stable
 - o +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - o +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - o +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - o +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - o >+2000 mOhms ----- 0 Points ----- Open Failure
- **Humidity**
 - o <= +5.0 mOhms ----- 191 Points ----- Stable
 - o +5.1 to +10.0 mOhms ----- 1 Points ----- Minor
 - o +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - o +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - o +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - o >+2000 mOhms ----- 0 Points ----- Open Failure

HLE-125-02-S-DV-A\TSM-125-01-S-DV-A (30u" Gold)**192 LLCR test points**

- **Initial** -----7.80mOhms Max
- **Durability 100 cycles**
 - o <= +5.0 mOhms ----- 192 Points ----- Stable
 - o +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - o +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - o +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - o +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - o >+2000 mOhms ----- 0 Points ----- Open Failure
- **Thermal**
 - o <= +5.0 mOhms ----- 192 Points ----- Stable
 - o +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - o +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - o +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - o +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - o >+2000 mOhms ----- 0 Points ----- Open Failure
- **Humidity**
 - o <= +5.0 mOhms ----- 189 Points ----- Stable
 - o +5.1 to +10.0 mOhms ----- 3 Points ----- Minor
 - o +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - o +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - o +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - o >+2000 mOhms ----- 0 Points ----- Open Failure

DATA SUMMARIES**LLCR Durability: HLE-125-02-L-DV-A\TSM-125-01-L-DV-A (10u" Gold)**

- 1) A total of 192 points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. $\leq +5.0$ mOhms:----- Stable
 - b. $+5.1$ to $+10.0$ mOhms:----- Minor
 - c. $+10.1$ to $+15.0$ mOhms:----- Acceptable
 - d. $+15.1$ to $+50.0$ mOhms:----- Marginal
 - e. $+50.1$ to $+2000$ mOhms:----- Unstable
 - f. $>+2000$ mOhms:----- Open Failure

LLCR Measurement Summaries by Pin Type				
Date	2012-3-12	2012-3-13	2012-3-26	2012-4-6
Room Temp (Deg C)	22	22	22	22
Rel Humidity (%)	36	41	38	31
Technician	Troy Cook	Troy Cook	Troy Cook	Troy Cook
mOhm values	Actual Initial	Delta 100 Cycles	Delta Thermal	Delta Humidity
Pin Type 1: Signal				
Average	6.69	0.46	0.55	0.77
St. Dev.	0.57	0.38	0.57	0.86
Min	5.05	0.00	0.01	0.00
Max	9.00	1.88	4.40	6.18
Summary Count	192	192	192	192
Total Count	192	192	192	192

LLCR Delta Count by Category						
	Stable	Minor	Acceptable	Marginal	Unstable	Open
mOhms	≤ 5	$>5 \text{ \& } \leq 10$	$>10 \text{ \& } \leq 15$	$>15 \text{ \& } \leq 50$	$>50 \text{ \& } \leq 1000$	>1000
100 Cycles	192	0	0	0	0	0
Thermal	192	0	0	0	0	0
Humidity	191	1	0	0	0	0

DATA SUMMARIES Continued**LLCR Durability: HLE-125-02-S-DV-A\TSM-125-01-S-DV-A (30u" Gold)**

- 1) A total of 192 points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. $\leq +5.0$ mOhms: ----- Stable
 - b. $+5.1$ to $+10.0$ mOhms: ----- Minor
 - c. $+10.1$ to $+15.0$ mOhms: ----- Acceptable
 - d. $+15.1$ to $+50.0$ mOhms: ----- Marginal
 - e. $+50.1$ to $+2000$ mOhms: ----- Unstable
 - f. $>+2000$ mOhms: ----- Open Failure

LLCR Measurement Summaries by Pin Type				
Date	2012-3-12	2012-3-13	2012-3-26	2012-4-6
Room Temp (Deg C)	22	21	22	22
Rel Humidity (%)	37	44	38	31
Technician	Troy Cook	Troy Cook	Troy Cook	Troy Cook
mOhm values	Actual Initial	Delta 100 Cycles	Delta Thermal	Delta Humidity
Pin Type 1: Signal				
Average	6.31	0.55	0.37	0.64
St. Dev.	0.40	0.37	0.33	0.85
Min	5.55	0.01	0.00	0.01
Max	7.80	2.05	1.98	7.40
Summary Count	192	192	192	192
Total Count	192	192	192	192

LLCR Delta Count by Category						
	Stable	Minor	Acceptable	Marginal	Unstable	Open
mOhms	≤ 5	$>5 \text{ \& } \leq 10$	$>10 \text{ \& } \leq 15$	$>15 \text{ \& } \leq 50$	$>50 \text{ \& } \leq 1000$	>1000
100 Cycles	192	0	0	0	0	0
Thermal	192	0	0	0	0	0
Humidity	189	3	0	0	0	0

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Part description: HLE/TSM	

EQUIPMENT AND CALIBRATION SCHEDULES

Equipment #: MO-04

Description: Multimeter /Data Acquisition System

Manufacturer: Keithley

Model: 2700

Serial #: 0798688

Accuracy: See Manual

... Last Cal: 04/30/2011, Next Cal: 04/30/2012

Equipment #: THC-02

Description: Temperature/Humidity Chamber

Manufacturer: Thermotron

Model: SE-1000-6-6

Serial #: 31808

Accuracy: See Manual

... Last Cal: 02/16/2012, Next Cal: 02/16/2013

Equipment #: TSC-01

Description: Vertical Thermal Shock Chamber

Manufacturer: Cincinnatti Sub Zero

Model: VTS-3-6-6-SC/AC

Serial #: 10-VT14993

Accuracy: See Manual

... Last Cal: 05/18/2011, Next Cal: 05/18/2012